

# Physics 5403: Computational Physics – Project 1

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due date: Sep 6, 2022

## Potential of a dipole (100 points)

A  $\text{Na}^+$  ion (charge  $+e$ ) is located on the positive  $x$ -axis at a distance of  $5\text{\AA}$  from the origin. A  $\text{Cl}^-$  ion (charge  $-e$ ) is located on the negative  $x$ -axis, also a distance of  $5\text{\AA}$  from the origin. In this project, you will explore the electric potential produced on the  $x$ -axis by these two charges. Specifically, you will compare the exact potential with the dipole approximation.

- Derive the dipole approximation by Taylor expanding the potential for distances large compared to the separation between the charges. Keep the lowest order non-vanishing term.
- Write a program which calculates the exact electric potential  $V_{\text{exa}}$  and the dipole approximation  $V_{\text{dip}}$  of the two charges on the  $x$ -axis in the interval  $[-x_{\text{max}}, x_{\text{max}}]$  using  $M$  equidistant points. The program should also calculate  $\Delta V = |V_{\text{exa}} - V_{\text{dip}}|$ .
- Think about how to choose reasonable values for the parameters  $x_{\text{max}}$  and  $M$ . Run the simulation for your chosen values of  $x_{\text{max}}$  and  $M$ . Plot  $V_{\text{exa}}$  and  $V_{\text{dip}}$  vs.  $x$ .
- What behavior do you expect for the difference  $\Delta V$  as a function of  $x$ ?
- Write a program which fits  $\Delta V$  to a power law,  $\Delta V = cx^{-n}$  with given exponent  $n$  but unknown “floating” prefactor  $c$  for all  $x > x_{\text{fit}}$ . The answer to c) should tell you which  $n$  to use. Think about reasonable values for  $x_{\text{fit}}$ .
- Run the fit program and plot  $\Delta V$  vs.  $x$  together with the power law resulting from your fit. Compare the fit value of  $c$  with the expected value. Discuss the result.

## Bonus: 2 Numerical differentiation (10 points)

Numerically differentiate the function given in the file `function.dat` on the class web site. Vary the step width  $h$ , and analyze how the systematic and random error change.